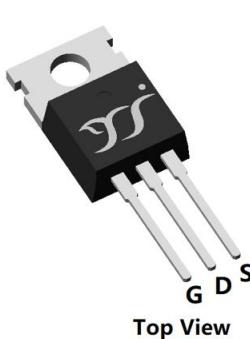
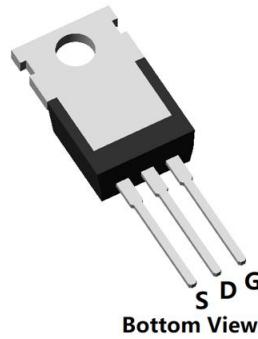




## N-Channel Enhancement Mode Field Effect Transistor

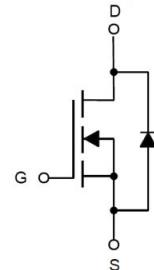


Top View



Bottom View

TO-220



### Product Summary

- $V_{DS}$  60V
- $I_D$  90A
- $R_{DS(ON)}$  (at  $V_{GS}=10V$ )  $<5.4m\Omega$
- 100% EAS Tested
- 100%  $\nabla V_{DS}$  Tested

### General Description

- Split gate trench MOSFET technology
- Excellent package for heat dissipation
- High density cell design for low  $R_{DS(ON)}$
- Epoxy Meets UL 94 V-0 Flammability Rating
- Halogen Free
- Part no. with suffix "Q" means AEC-Q101 qualified

### Applications

- Power switching application
- Uninterruptible power supply
- DC-DC convertor

### ■ Limiting Values

Parameter	Conditions		Symbol	Min	Max	Unit
Drain-source Voltage	$T_A=25^\circ C, V_{GS}=10V$	$T_A=100^\circ C, V_{GS}=10V$	$V_{DS}$	-	60	V
Gate-source Voltage			$V_{GS}$	-20	20	
Continuous Drain Current (Note 1,2)	Steady-State	$T_A=25^\circ C, V_{GS}=10V$	$I_D$	-	20	A
Continuous Drain Current (Note 1,2)		$T_A=100^\circ C, V_{GS}=10V$		-	14	
Continuous Drain Current (Note 1,3)	Steady-State	$T_c=25^\circ C, V_{GS}=10V$ , Chip limitation	$I_D$	-	90	
Continuous Drain Current (Note 1,3)		$T_c=100^\circ C, V_{GS}=10V$		-	63	
Pulsed Drain Current	$T_c=25^\circ C, t_p \leq 10\mu s$		$I_{DM}$	-	350	
Maximum Body-Diode Continuous Current	$T_c=25^\circ C$		$I_S$		75	
Avalanche Energy (non-repetitive)	$T_j=25^\circ C, V_G=10V, R_G=25\Omega, L=0.5mH, I_{AS}=23.5A$		EAS	-	138	mJ
Total Power Dissipation (Note 1,2)	Steady-State	$T_A=25^\circ C$	$P_D$	-	4.2	W
Total Power Dissipation (Note 1,2)		$T_A=100^\circ C$		-	2.1	
Total Power Dissipation (Note 1,3)	Steady-State	$T_c=25^\circ C$		-	88	
Total Power Dissipation (Note 1,3)		$T_c=100^\circ C$		-	44	
Junction and Storage Temperature Range			$T_J, T_{STG}$	-55	175	°C

### ■ Thermal Resistance

Parameter	Symbol	Typ	Max	Units
Thermal Resistance Junction-to-Ambient (Note 2)	$R_{\theta JA}$	-	35	°C/W
Thermal Resistance Junction-to-Case	$R_{\theta JC}$	-	1.7	

### ■ Ordering Information (Example)

PREFERRED P/N	PACKING CODE	Marking	MINIMUM PACKAGE(pcs)	INNER BOX QUANTITY(pcs)	OUTER CARTON QUANTITY(pcs)	DELIVERY MODE
YJP5D4G06HQ	B1	YJP5D4G06H	50	/	5000	Tube



## ■ Electrical Characteristics

Parameter	Symbol	Conditions	Min	Typ	Max	Units
<b>Static Parameter</b>						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V,I <sub>D</sub> =250μA,T <sub>j</sub> =25°C	60	-	-	V
		V <sub>GS</sub> =0V,I <sub>D</sub> =1mA,T <sub>j</sub> =25°C	60	-	-	V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =60V,V <sub>GS</sub> =0V,T <sub>j</sub> =25°C	-	-	1	μA
		V <sub>DS</sub> =60V,V <sub>GS</sub> =0V,T <sub>j</sub> =125°C	-	-	100	
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V,V <sub>DS</sub> =0V,T <sub>j</sub> =25°C	-	-	±100	nA
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> ,I <sub>D</sub> =250μA,T <sub>j</sub> =25°C	2	3	4	V
Static Drain-Source On-Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10V,I <sub>D</sub> =45A,T <sub>j</sub> =25°C	-	4.3	5.4	mΩ
Diode Forward Voltage	V <sub>SD</sub>	I <sub>S</sub> =45A,V <sub>GS</sub> =0V,T <sub>j</sub> =25°C	-	0.89	1.2	V
Gate Resistance	R <sub>G</sub>	f=1MHz,T <sub>j</sub> =25°C	-	1.5	-	Ω
<b>Dynamic Parameters</b>						
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> =30V,V <sub>GS</sub> =0V,f=1MHz,T <sub>j</sub> =25°C	-	1530	-	pF
Output Capacitance	C <sub>oss</sub>		-	460	-	
Reverse Transfer Capacitance	C <sub>rss</sub>		-	16	-	
<b>Switching Parameters</b>						
Total Gate Charge	Q <sub>g</sub>	V <sub>GS</sub> =10V,V <sub>DS</sub> =30V,I <sub>D</sub> =45A,T <sub>j</sub> =25°C	-	28	-	nC
Gate-Source Charge	Q <sub>gs</sub>		-	7.5	-	
Gate-Drain Charge	Q <sub>gd</sub>		-	9	-	
Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> =45A,di/dt=100A/μs,V <sub>GS</sub> =0V,V <sub>R</sub> =30V,T <sub>j</sub> =25°C	-	16	-	nC
Reverse Recovery Time	t <sub>rr</sub>		-	25	-	ns
Turn-on Delay Time	t <sub>D(on)</sub>	V <sub>GS</sub> =10V,V <sub>DS</sub> =30V,I <sub>D</sub> =45A,R <sub>L</sub> =0.67Ω,R <sub>GEN</sub> =3Ω,T <sub>j</sub> =25°C	-	12	-	ns
Turn-on Rise Time	t <sub>r</sub>		-	68	-	
Turn-off Delay Time	t <sub>D(off)</sub>		-	21	-	
Turn-off Fall Time	t <sub>f</sub>		-	10	-	

Note:

- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- The value of R<sub>θJA</sub> is measured with the device mounted on the 40mm\*40mm\*1.1mm single layer FR-4 PCB board with 1 in<sup>2</sup> pad of 2oz. Copper, in the still air environment with T<sub>A</sub>=25°C. The maximum allowed junction temperature of 175°C. The value in any given application depends on the user's specific board design.
- Thermal resistance from junction to soldering point (on the exposed drain pad).

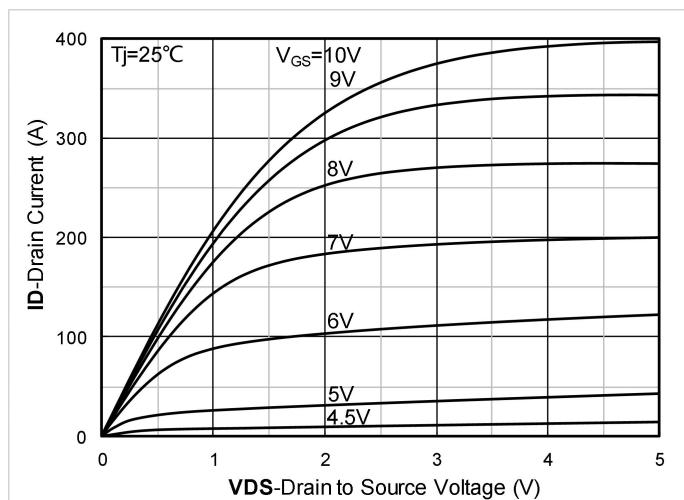
**■Typical Electrical and Thermal Characteristics Diagrams**

Figure 1. Output Characteristics; typical values

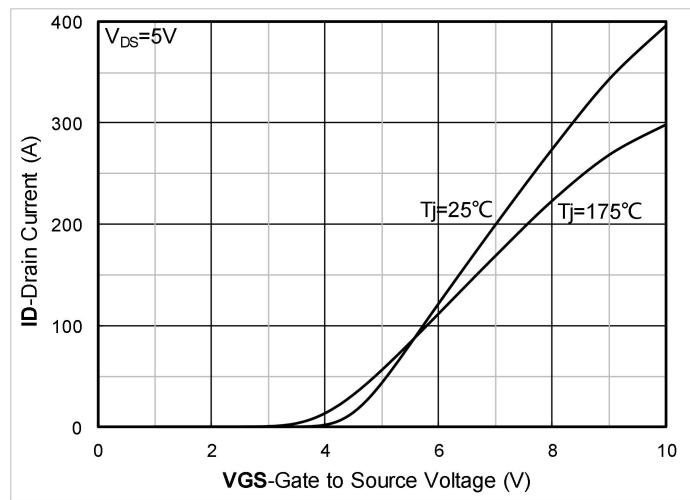


Figure 2. Transfer Characteristics; typical values

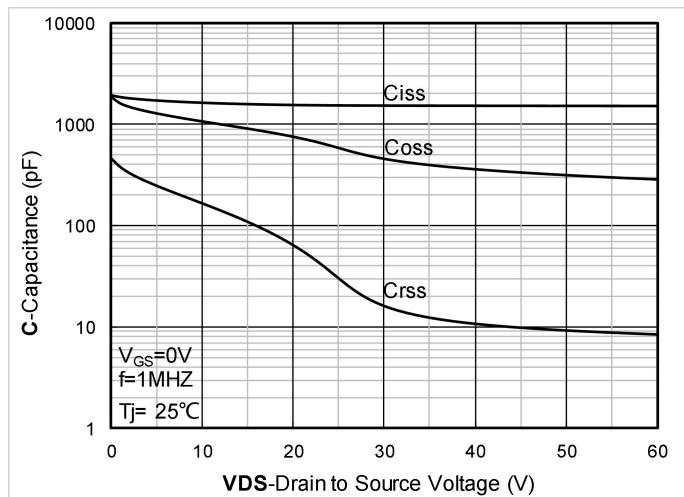


Figure 3. Capacitance Characteristics; typical values

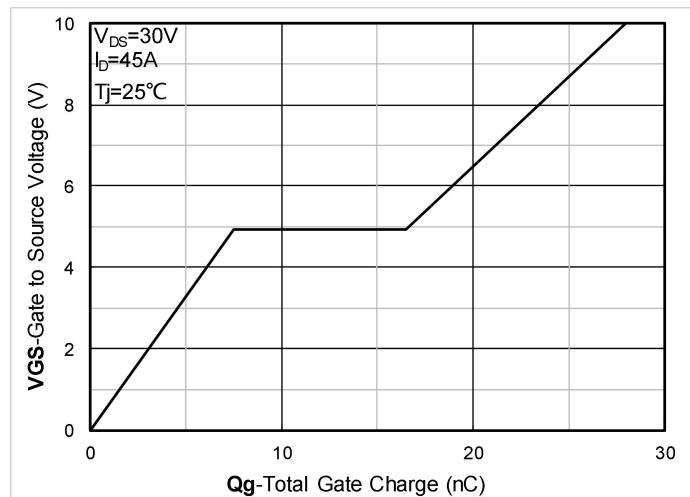


Figure 4. Gate Charge; typical values

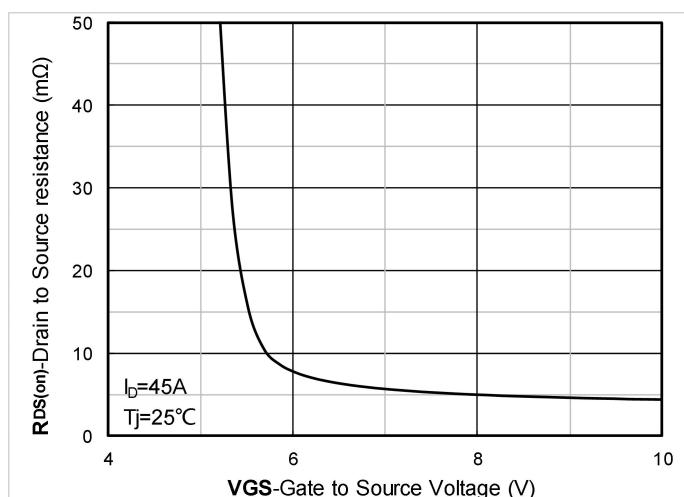


Figure 5. On-Resistance vs. Gate to Source Voltage; typical values

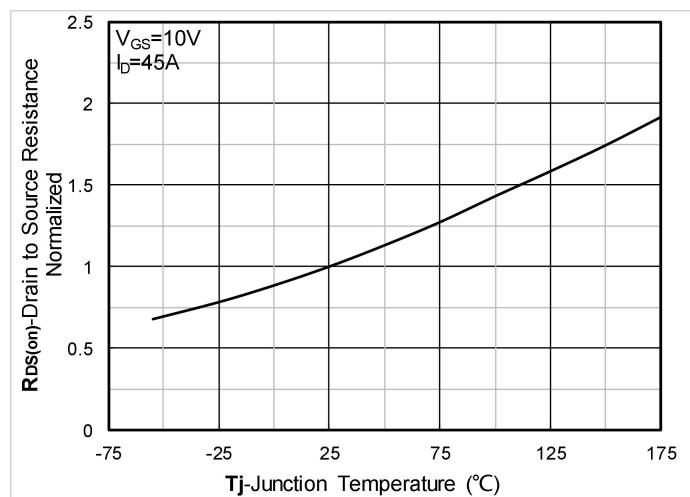


Figure 6. Normalized On-Resistance

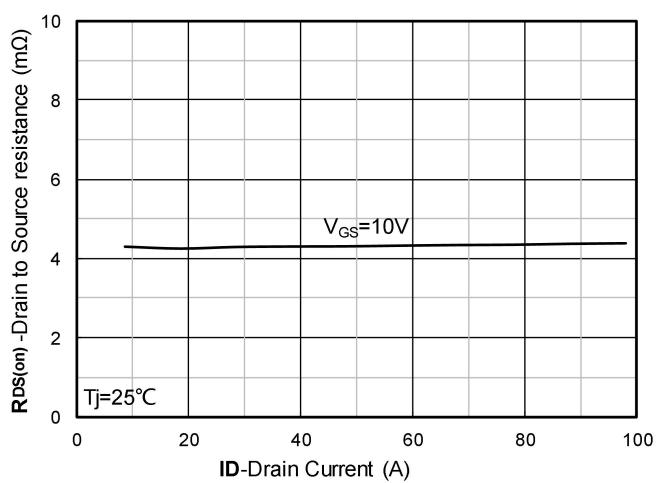


Figure 7. RDS(on) vs. Drain Current; typical values

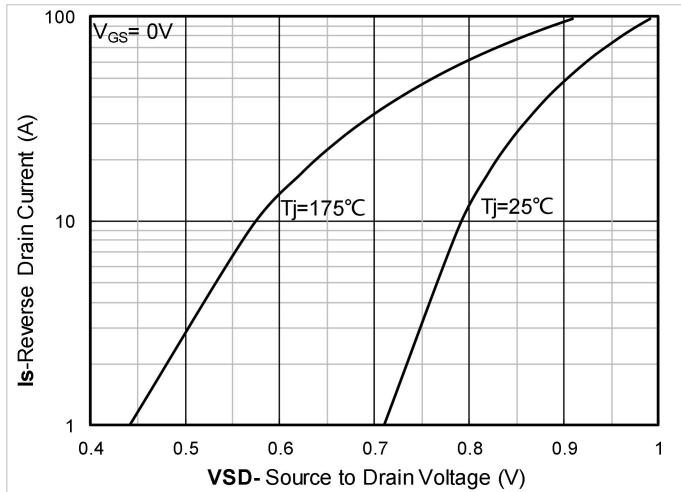


Figure 8. Forward characteristics of reverse diode; typical values

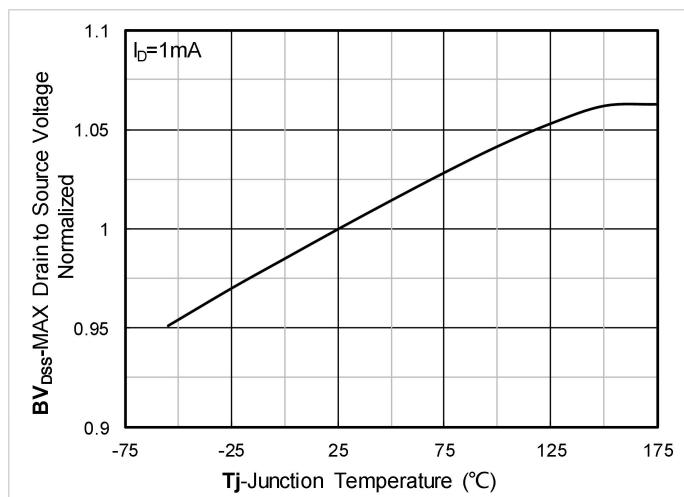


Figure 9. Normalized breakdown voltage

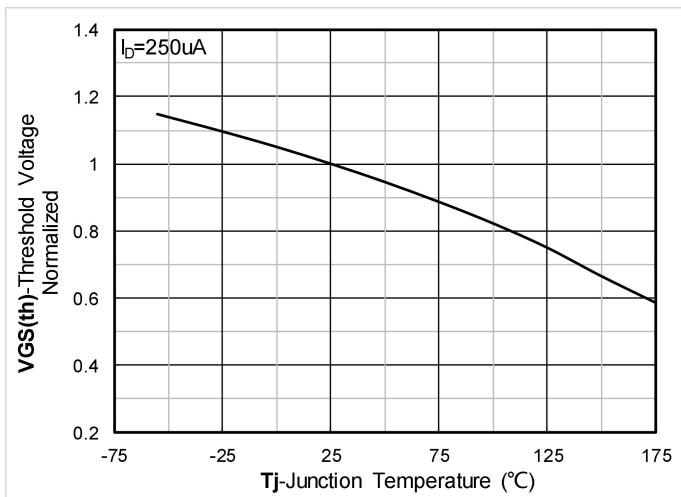


Figure 10. Normalized Threshold voltage

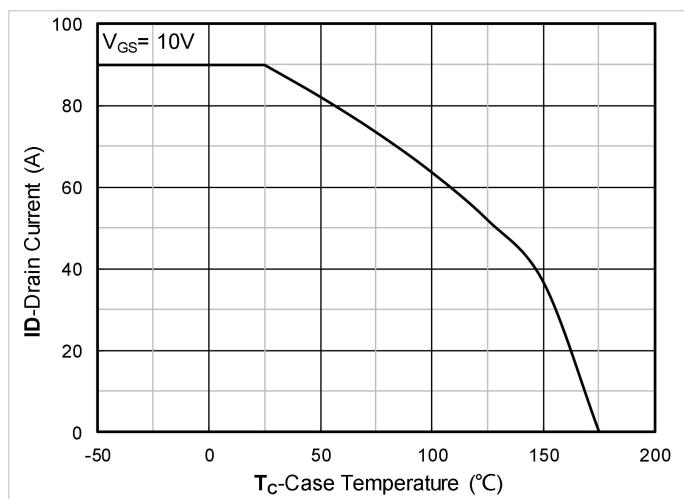


Figure 11. Current dissipation

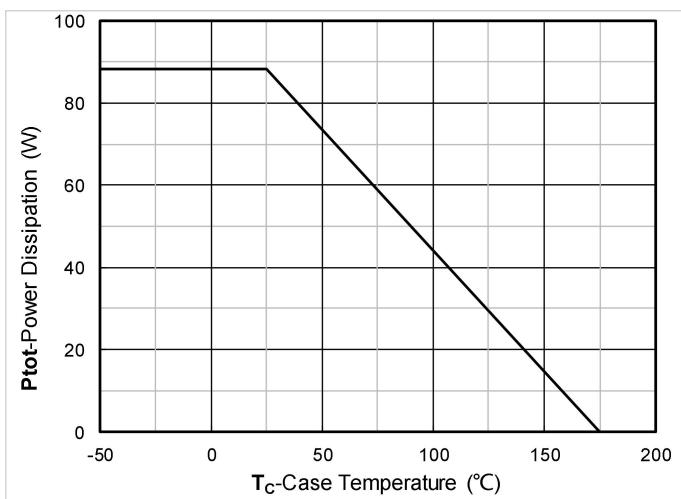


Figure 12. Power dissipation



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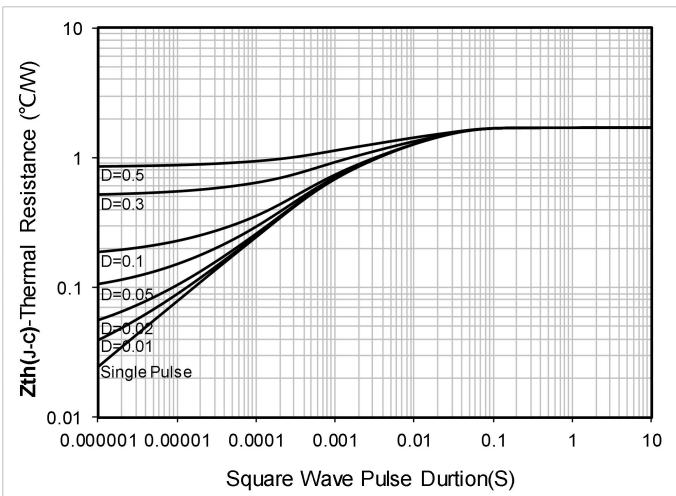


Figure 13. Maximum Transient Thermal Impedance

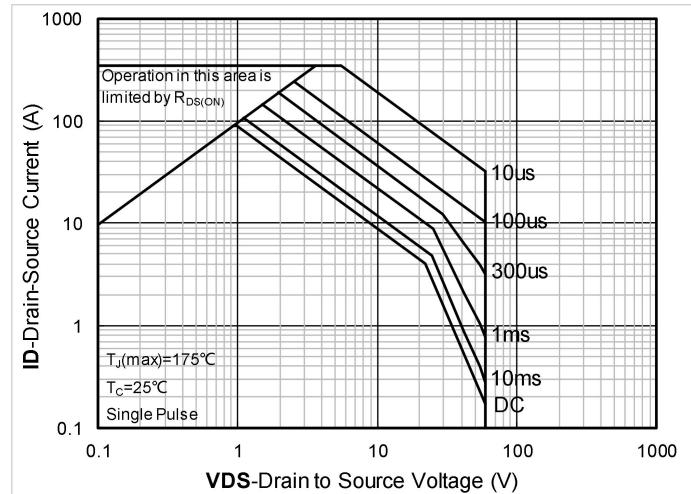


Figure 14. Safe Operation Area

## ■ Test Circuits & Waveforms

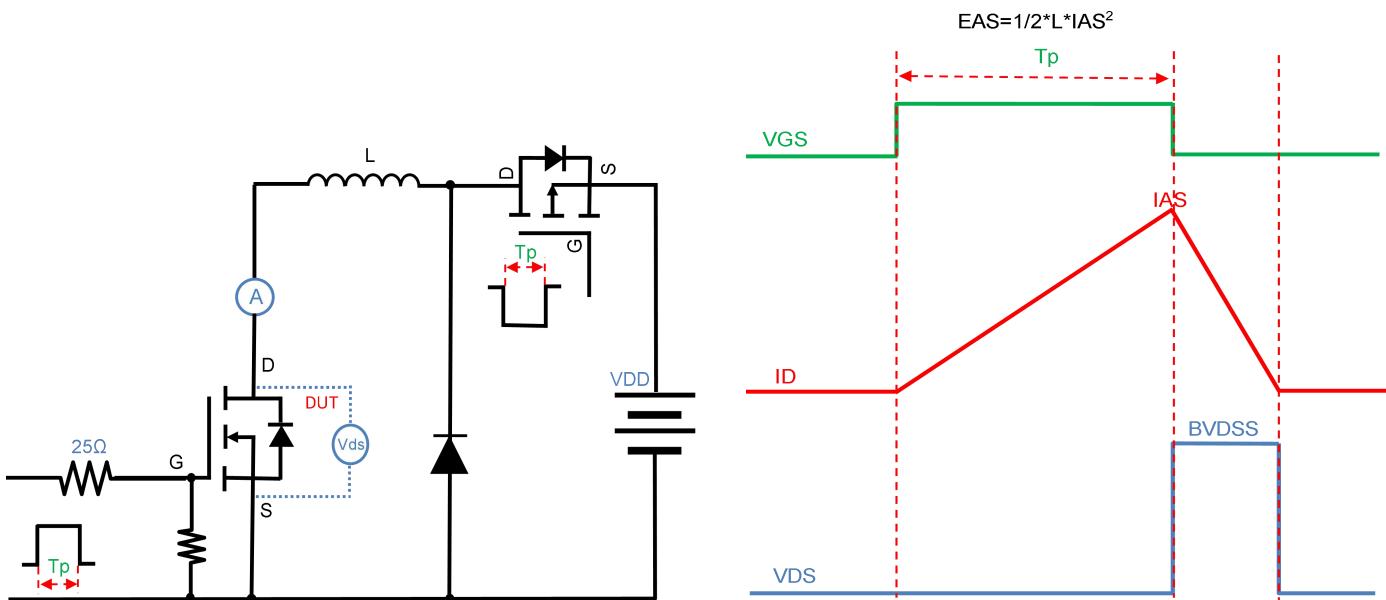


Figure A. Unclamped Inductive Switching (UIS) Test Circuit & Waveform

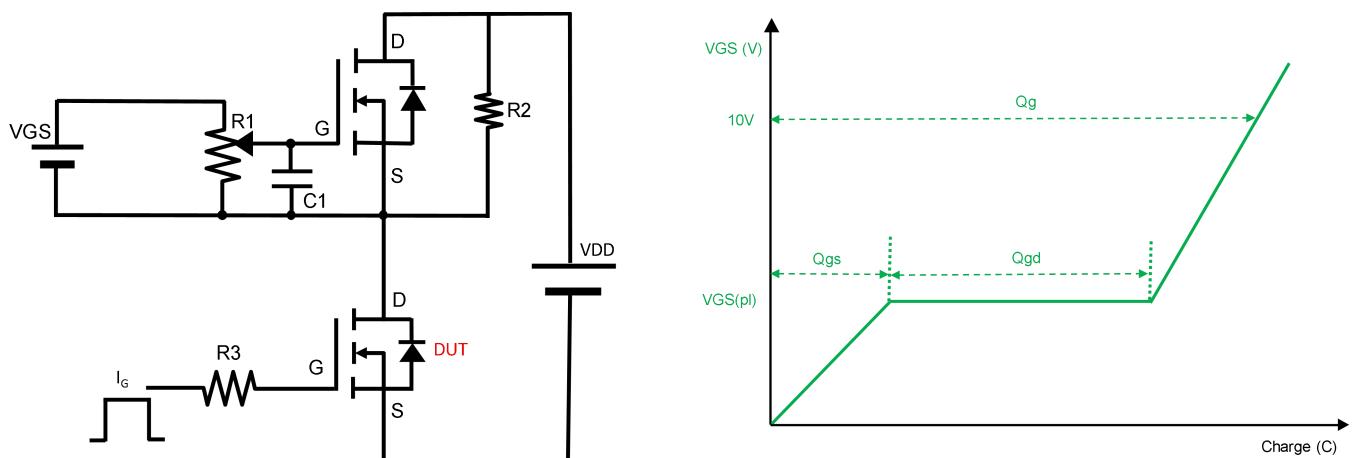


Figure B. Gate Charge Test Circuit & Waveform

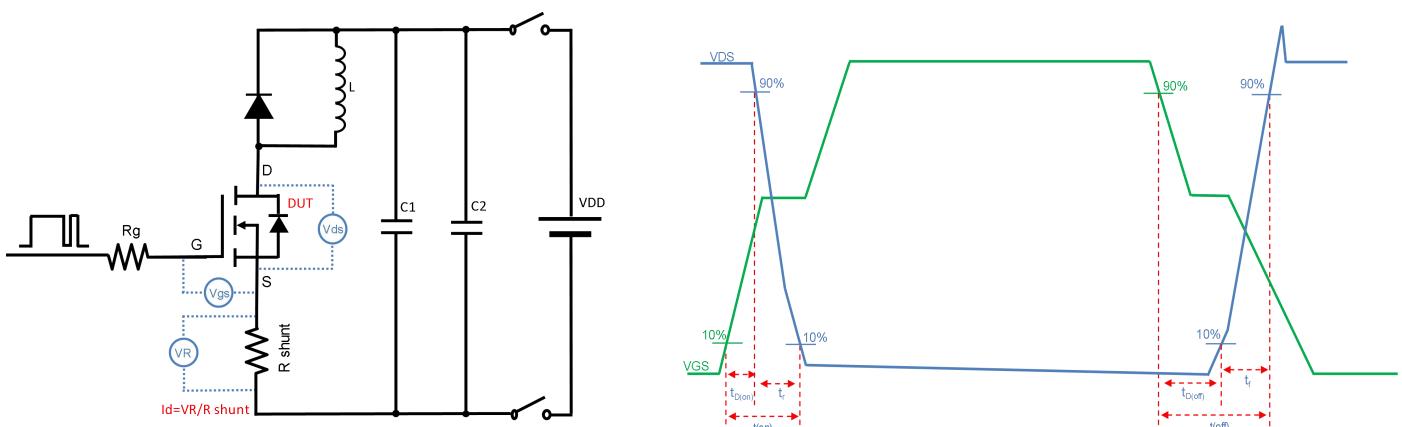


Figure C. Resistive Switching Test Circuit & Waveform

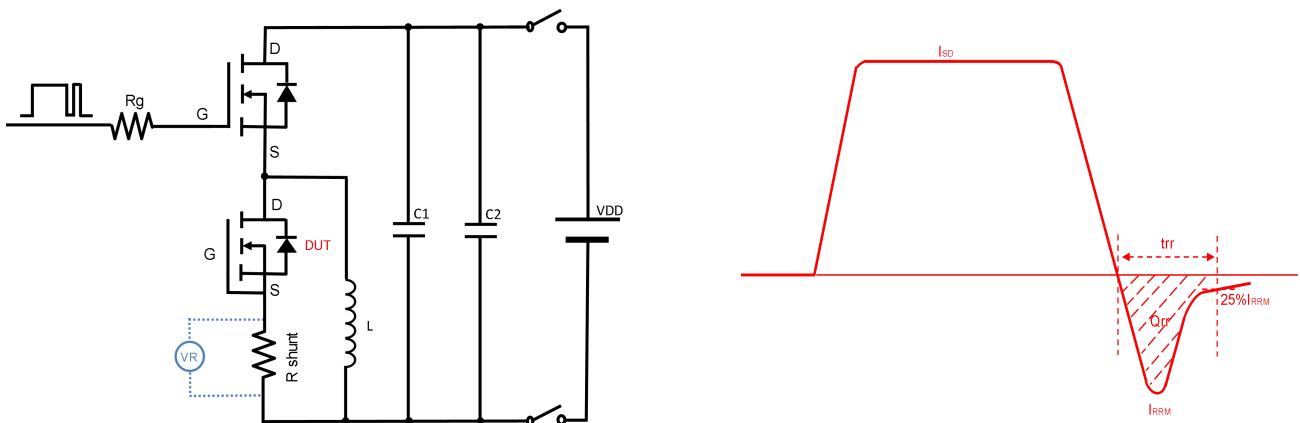
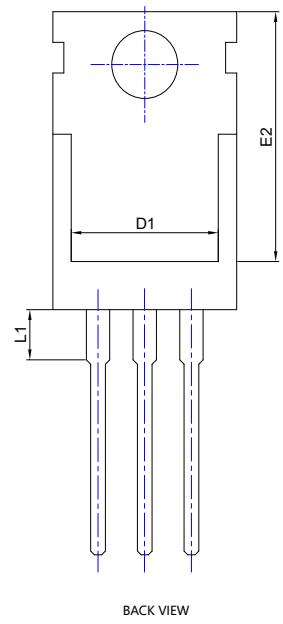
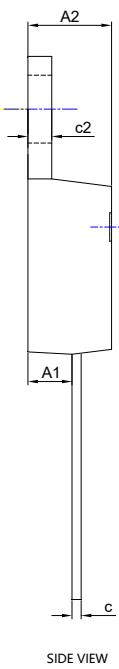
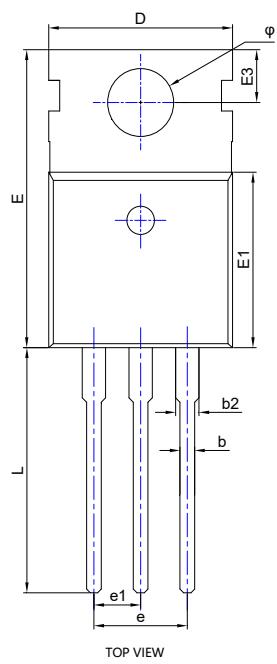


Figure D. Diode Recovery Test Circuit & Waveform



## ■ TO-220AB-E Package information



SYMBOL	INCHES		Millimeter	
	MIN.	MAX.	MIN.	MAX.
A1	0.093	0.114	2.350	2.900
A2	0.176	0.184	4.470	4.670
b	0.028	0.036	0.710	0.910
b2	0.048	0.054	1.220	1.360
c	0.019	0.024	0.470	0.600
c2	0.047	0.055	1.200	1.400
D	0.382	0.408	9.700	10.370
D1	0.276	0.350	7.000	8.890
E	0.579	0.622	14.700	15.800
E1	0.350	0.373	8.900	9.470
E2	0.463	0.535	11.750	13.600
E3	0.108BSC		2.740BSC	
e	0.200BSC		5.080BSC	
e1	0.100BSC		2.540BSC	
L	0.508	0.583	12.900	14.800
L1	0.100	0.151	2.540	3.840
φ	0.142	0.154	3.600	3.900

NOTE:  
1.PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS.  
2.TOLERANCE 0.1mm UNLESS OTHERWISE SPECIFIED.



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REV.	EFFECTIVE DATE	REVISION HISTORY	PREPARED
1.0	2024.11.5	New release	Haijun Ding